

# Search Notes



Application/Control No.

10/803,999

Examiner

Sin J. Lee

Applicant(s)/Patent under  
Reexamination

TAKAHASHI ET AL.

Art Unit

1752

## SEARCHED

Class	Subclass	Date	Examiner
430	271.1	5-29 -05	SJL
↓	278.1	↓	↓
↓	270.1	↓	↓
↓	944	↓	↓

## INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

## SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
Structure Search for formula (I) of cl. #2	11-7 -05	SJL
Structure Search for formula (I-b) of cl. #5	↓	↓